Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/672,174	TAKAMI ET AL.
Examiner	Art Unit

1772

Christopher P. Bruenjes

SEARCHED				
Class	Subclass	Date	Examiner	
UPDATED	SEARCH	1/12/2006	СВ	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH (INCLUDING SEAF		)
	DATE	EXMR
UPDATED SEARCH	1/12/2006	СВ